Application/Control No. Applicant(s)/Patent Under Reexamination 10/808,970 BAIADA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 TAN Q. NGUYEN 3661 **U.S. PATENT DOCUMENTS Document Number** Date Name Country Code-Number-Kind Code Classification MM-YYYY US-6,507,782 B1 01-2003 Rumbo et al. 701/121 US-2004/0039518 A1 02-2004 Jasselin, Philippe 701/120 В 07-2004 Biffar, Peter US-2004/0124977 A1 С 340/539.13 US-D US-Ε US-F US-G US-Н US-US-USκ US-US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Country Code-Number-Kind Code Classification MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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